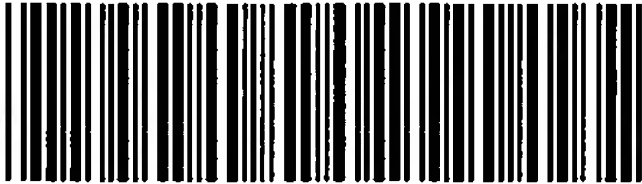


<div>Search Notes</div> <div></div>	Application/Contr I N .	Applicant(s)/Patent under Reexamination	
	10/602,859	CASTERLIN ET AL.	
	Examiner	Art Unit	
	Jacob Cheu	1641	

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422	50 58	6/6/06	J
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436	164		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
FAST S71 Inventn (palm)	6/6/06	J